Special Issue

Artificial Intelligence in Remote Sensing: Advancing Geospatial Analysis for Environmental Monitoring

Message from the Guest Editors

This Special Issue aims to explore and showcase cutting-edge applications of artificial intelligence (AI) in remote sensing and geospatial analysis for environmental monitoring. We seek to highlight how AI technologies are revolutionizing our ability to collect, process, analyze, and interpret large-scale environmental data from various remote sensing platforms. The Special Issue will cover a wide range of topics, including, but not limited to, the following:

- Machine learning and deep learning for satellite image analysis;
- Al-driven change detection in time-series remote sensing data;
- Multi-sensor data fusion using AI techniques;
- Al applications in hyperspectral image analysis;
- Object detection and tracking in remote sensing imagery;
- Al-powered predictive modeling for environmental phenomena;
- Natural language processing for geospatial metadata analysis.

Guest Editors

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Deadline for manuscript submissions

closed (20 August 2025)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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